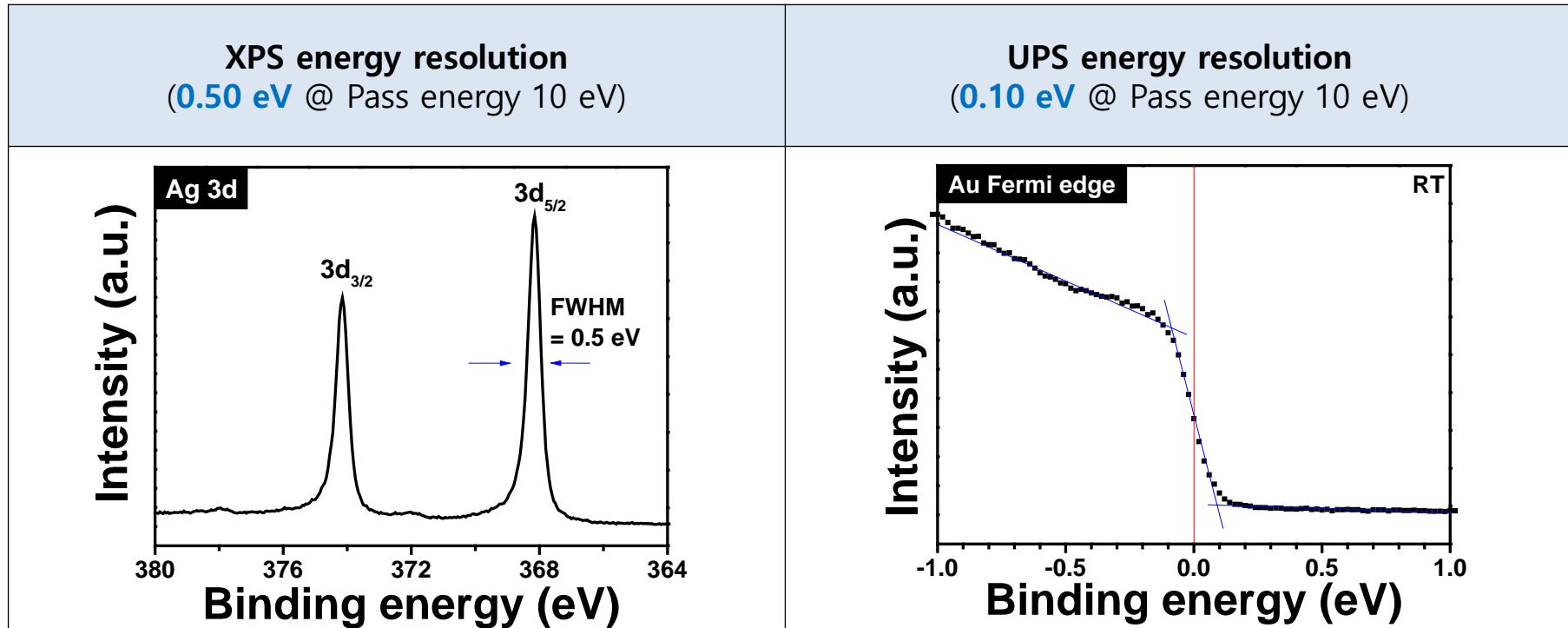


부서	대상 장비(기기코드)	공지 성능	공지 주기
나노표면 연구팀	엑스선/자외선 광전자 분광기 (Micro X-ray/UV Photoelectron Spectrometer, QM12)	<ul style="list-style-type: none"> • Base pressure : 2.0×10^{-10} Torr • Photon source (XPS) : Monochromatic Al-Kα & Dual source • Photon source (UPS) : He I and II • Energy resolution (XPS) < 0.5 eV @ Ep 10 eV • Energy resolution (UPS) < 0.1 eV @ Ep 10 eV • Spatial resolution (XPS mapping) $\approx 10 \mu\text{m}$ • Ar+ ion source energy : 500 ~ 4 keV • Ar+ ion cluster source energy : 5 ~ 20 keV - cluster: 500, 1000, 2000, 3000 • Cooling and Heating : -150 ~ 450°C 	연 4회 (1월, 4월, 7월, 10월)
	엑스선/극자외선 광전자 분광분석기 (Micro X-ray/UV Photoelectron Spectromicroscopy, CJ109)	<ul style="list-style-type: none"> • Base pressure : 2.0×10^{-9} Torr • Photon source (XPS) : Monochromatic Al-Kα (1486.6 eV) • Photon source (UPS) : He I and II • Energy resolution (XPS) < 0.5 eV @ Ep 10 eV • Energy resolution (UPS) < 0.1 eV @ Ep 10 eV • Ar+ ion source energy : 500 ~ 4 keV • Ar+ ion cluster source energy : 5 ~ 20 keV 	연 4회 (1월, 4월, 7월, 10월)

분석지원장비 상태 보고서

Code(기기코드)	Instrument (장비명)
QM12	Micro X-ray/UV Photoelectron Spectrometer (엑스선/자외선 광전자 분광기)
Report Date (일시)	2019.07.01



분석지원장비 상태 보고서

Code(기기코드)	Instrument (장비명)
CJ109	Micro X-ray/UV Photoelectron Spectromicroscopy (엑스선/극자외선 광전자 분광분석기)
Report Date (일시)	2019.07.04

